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WEBINARS

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Quantum Efficiency Measurements: Fundamentals for Solar Cell Research, Part 2

Wednesday, February 21, 2024 1:00 PM - 2:00 PM EST

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Presented by



In part two of this series, representatives from MKS Newport present an in-depth discussion on equipment and test configurations used for cutting-edge cell development such as perovskites and multi-junction cells. These configuration topics include device interfacing, light generation techniques, and signal detection. They discuss specific requirements that are needed to take these measurements as well as the key challenges researchers run into during experimentation. In addition to quantum efficiency measurements, they also review I-V curve generation and analysis for solar module level parameter testing. Join MKS Newport experts to learn and dig into the world of solar cell design measurements and how to set up a lab for success. Presented by MKS Newport.



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